



BEST PAPER AWARD

The Best Paper Award Committee of the
*35th European Symposium on Reliability of Electron Devices,
Failure Physics and Analysis, ESREF 2024, Parma, Italy, September 23-26*

presents the Best Paper Award to the paper entitled
***Reliability and Failure Analysis of
AlGaN/GaN HEMT with NiPtAu and PtAu Gate***

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